Application/Control No. Applicant(s)/Patent Under Reexamination 10/035,518 CHAN ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 David A. Zarneke 2827 **U.S. PATENT DOCUMENTS** Document Number Date Name Classification Country Code-Number-Kind Code MM-YYYY US-6,225,699 05-2001 Ference et al. Α 257/777 US-5,977,640 11-1999 Bertin et al. 257/777 12-2000 US-6,160,715 С Degani et al. 361/767 D US-6,154,370 11-2000 Degani et al. 361/761 Ε US-5,646,828 07-1997 Degani et al. 361/715 F US-US-G Н US-1 US-US-J Κ US-US-US-М **FOREIGN PATENT DOCUMENTS** Document Number Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Ρ Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U ٧ W

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